

<b>Notice of References Cited</b>	Application/Control No. 09/879,826	Applicant(s)/Patent Under Reexamination KEENER, BRYAN F.	
	Examiner Fred Ferris	Art Unit 2128	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0156127 A1	08-2003	KLEYMAN, VADIM	345/672
	B	US-6,686,914 B2	02-2004	Keener, Bryan F.	345/420
	C	US-6,614,430	09-2003	Rappoport, Ari	345/420
	D	US-5,742,288	04-1998	Nishizaka et al.	345/418
	E	US-5,615,319	03-1997	Metzger et al.	345/427
	F	US-5,581,672	12-1996	Letcher, Jr., John S.	345/420
	G	US-5,465,324	11-1995	Lee et al.	345/642
	H	US-5,696,848	12-1997	Patti et al.	382/254
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Repairing CAD Models", G. Barequet, IEEE 0-8186-8262-0/97, IEEE 1997
	V	"RSVP: A Geometric toolkit for Controlled Repair of Solid Models", G. Barequet et al, IEEE Transactions on Visualization and Computer Graphics, Vol. 4, No. 2, June 1998
	W	"Variable-Precision Rendering", X. Hao et al, I3D '2001, ACM Jan. 2001
	X	"Sensitivity Analysis Procedures for Geometric Programs: Computational Aspects", J.J. Dinkel et al, ACM Trans. on Math. Software, Vol. 4, No. 1, March 1978

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.